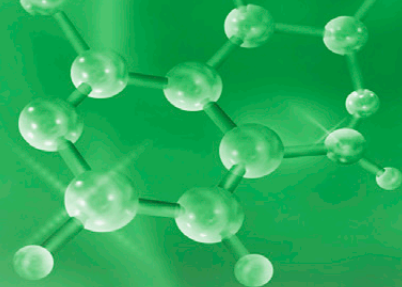


Xenometrix

The Power to Change Energy Into Information



EX-6600 SDD Secondary Target EDXRF

- ▶ Elemental analysis F(9) - U(92) from single ppm to 100% concentrations.
- ▶ Silicon Drift Detector (SDD) enables extremely high count rate applications with excellent energy resolution, suitable for both high and low z elements.
- ▶ Save cost and time!
Liquid Nitrogen FREE.
- ▶ Combining 300W tube power, secondary target mode and SDD technology lead to a workhorse instrument every laboratory can dream about.
- ▶ Close-coupled optics using secondary target mode allows greater flux and superior sensitivity.
- ▶ Eight customizable filters and eight secondary targets for fast and accurate determination of trace and minor elements.

The Ultimate in Analytical Performance

Xenometrix is a leading designer, manufacturer and marketer of Energy-Dispersive X-ray Fluorescence (EDXRF) systems and components for a wide range of industries and applications. Relying on more than

30 years experience in the field, Xenometrix provides quality and cost effective answers to real world analytical challenges by combining the latest technological developments with innovative engineering.

email: info@xenometrix.com
www.xenometrix.com

EX-6600 SDD

Xenometrix's EX-6600 SDD Energy Dispersive X-ray Fluorescence (EDXRF) spectrometer offers the ultimate in **sensitivity** and selectivity.

The Silicon Drift Detector (SDD) simultaneously delivers lower electronic noise and higher count rates which translates to higher energy resolution and faster results compared to a Si-PIN detector.

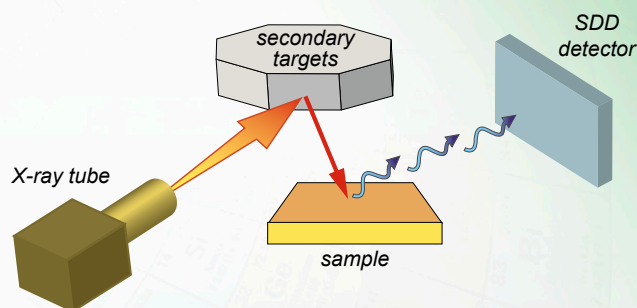
Eight **secondary targets** provide maximum sensitivity for fast and precise quantification even in difficult matrices such as alloy, plastic and geological samples. Targets are fully customizable to achieve **sub-ppm** detection limits.

The versatile EX-6600 SDD can analyze liquids, solids, slurries, powders, pellets and air filters and the analytical chamber accommodates samples of different shapes and sizes.

The integral design of the 10-position autosampler permits minimal operator intervention and allows automatic loading and unattended operation.

This **fast, accurate, easy-to-use** instrument has robust hardware and powerful analytical software to achieve low detection limits.

The Multi-Channel Acquisition resolution provides superior peak-to-background ratio for improved detector response.



Key Applications

Mining & Minerals

Metallurgical

Environmental

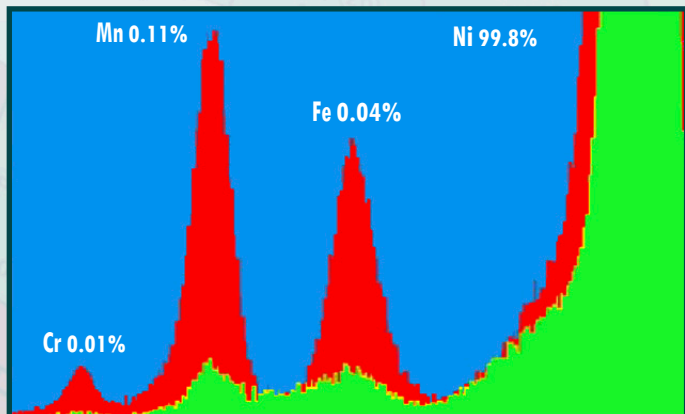
Petrochemical

Radioactive

Materials Research



Secondary Target Excitation



The green spectrum shows a Ni alloy containing 99.8% Ni and small amounts of Cr, Mn and Fe as impurities.

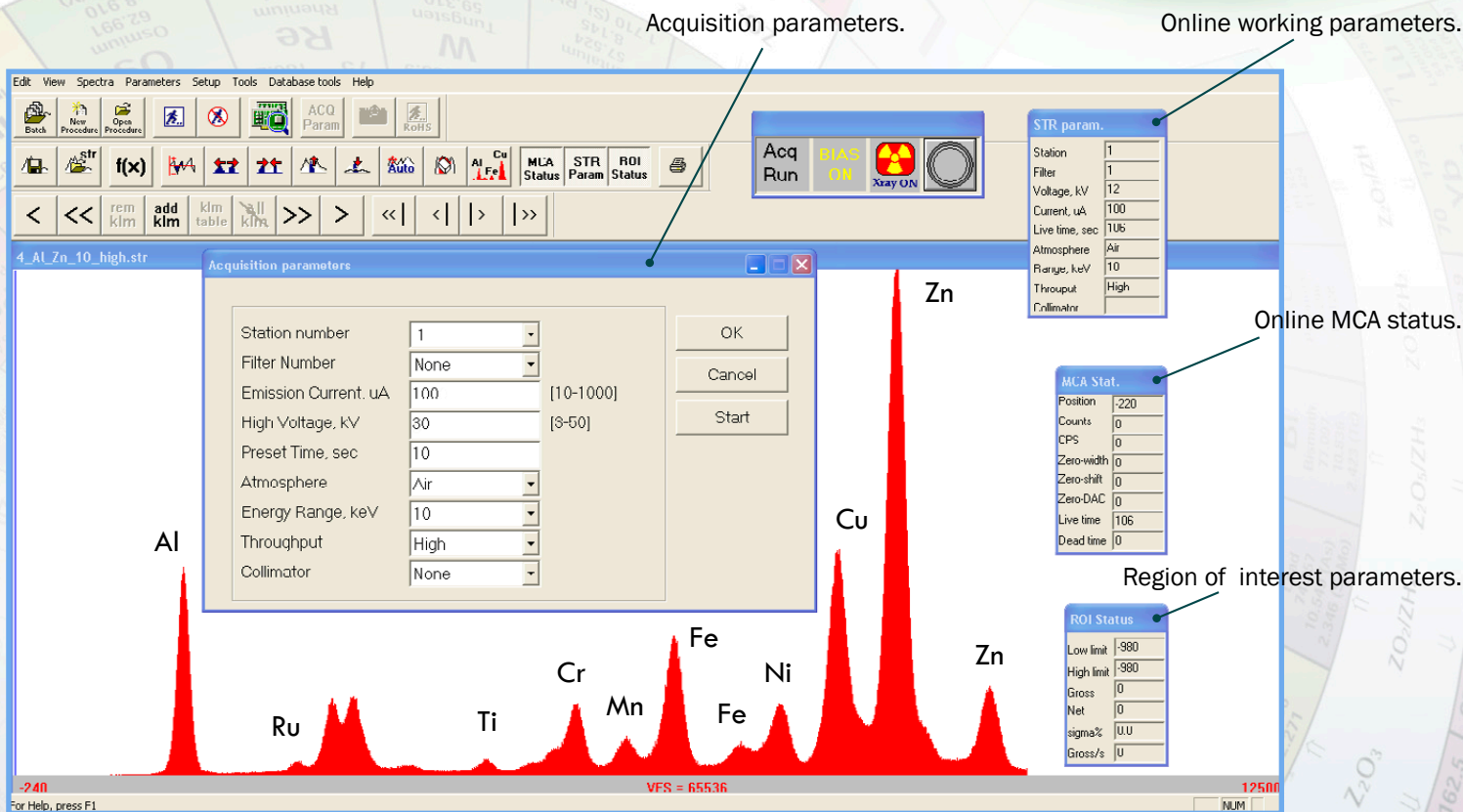
The response in direct excitation for these elements are muted by the absorption effect of the Ni signal. Using a Ni secondary target (Red Spectrum), the excitation of the Ni is less efficient, but the excitation efficiency for Fe, Mn and Cr is greatly enhanced, as shown by the peak responses for these elements.

EX-6600 SDD - Lab EDXRF spectrometer

SYSTEM SPECIFICATIONS	
Measurement Capability	
Detectable Range	F(9) - U(92).
Detectable Concentration	ppm - 100% (ppb in certain applications).
X-Ray Generation	
X-Ray Tube	Rh - anode standard (Mo, W, Ag, Cr optional).
X-Ray Source	60kV, 300W.
Excitation type	Direct and secondary target excitation.
Stability	Precision 0.1% at ambient temperature.
X-Ray Detection	
Detector	Silicon Drift Detector (SDD), liquid nitrogen FREE.
Resolution (FWHM)	136 eV \pm 5eV at 5.9 keV.
Window	Be.
General Features	
Auto sampler	10 positions.
Work atmosphere	Air/ Vacuum/ Helium.
Tube filters	8 software selectable.
Secondary targets	8 software selectable: Zr, Si, Ti, Fe, Ge, Mo, Sn, Gd.
Power Supply	115 VAC/60 Hz or 230 VAC/50 Hz.
Pulse Processing	Multi-channel analyzer.
Optics	Patented WAG [®] (Wide Angle Geometry).
System dimensions (L x W x H, cm)	Unpacked: 85 x 85 x 105, Packed: 145 x 95 x 135.
System weight	170kg (net), 220kg (gross).
Chamber dimensions	28cm diameter, H=5cm.
Computer	Integrated PC.
Software	
Operating Software	nEXt™ analysis package, running under Microsoft Windows™ XP + basic Fundamental Parameters.
Control	Automatic control of excitation, detection, sample handling and data processing.
Spectrum Processing	Automatic escape peak and background removal. Automatic peak deconvolution. Graphical statistics.
Quantitative Analysis Algorithms	Multi-element regression with inter-element corrections (six models available). Gross, net, fit and digital filter intensity methods.
Reporting	User-customizable data print out.
Options at additional cost (contact us for pricing)	18 pos. carousel autosampler. Sample spinner. Professional Fundamental Parameters.

Software environment (GUI)

Simple, straight forward, user friendly nEXt™ platform.



Worldwide Distributions:

NORTH AMERICA, LATIN AMERICA, EUROPE, ASIA, AUSTRALIA, AFRICA & MIDDLE EAST

Xenometrix Ltd. (Headquarters)

Ramat Gabriel Industrial Zone, 5 Hatasia St.,
Kiryat Hamada, Migdal Haemek 23000, Israel

Letters: P.O.B. 997
Migdal Haemek 23100, Israel

Tel: +972-4-9891313
Fax: +972-4-9891323

Xenometrix Inc.

8601 Cross Park Drive, Suite 200
Austin, TX 78754 USA

Phone: (512) 973-9229
Fax: (512) 973-9282

email: info@xenometrix.com
www.xenometrix.com